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Α

 $\mathsf{m}\Omega$ 

#### IPI09N03LA, IPP09N03LA

25

8.9

50

# **OptiMOS**<sup>®</sup>2 Power-Transistor

#### **Features**

- Ideal for high-frequency dc/dc converters
- N-channel
- Logic level
- Excellent gate charge x R<sub>DS(on)</sub> product (FOM)
- Very low on-resistance R DS(on)

• Superior thermal resistance

• 175 °C operating temperature

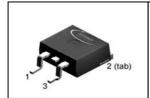
• dv/dt rated

P-TO263-3-2

P-TO262-3-1

 $I_{D}$ 

P-TO220-3-1



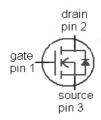


**Product Summary** 

 $R_{DS(on),max}$  (SMD version)



Туре	Package	Ordering Code	Marking
IPB09N03LA	P-TO263-3-2	Q67042-S4151	09N03LA
IPI09N03LA	P-TO262-3-1	Q67042-S4152	09N03LA
IPP09N03LA	P-TO220-3-1	Q67042-S4153	09N03LA



## **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C <sup>1)</sup>	50	А
		T <sub>C</sub> =100 °C	46	
Pulsed drain current	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C <sup>2)</sup>	350	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =45 A, $R_{\rm GS}$ =25 $\Omega$	75	mJ
Reverse diode dv/dt	dv/dt	$I_{\rm D}$ =50 A, $V_{\rm DS}$ =20 V, d <i>i</i> /d <i>t</i> =200 A/ $\mu$ s, $T_{\rm j,max}$ =175 °C	6	kV/μs
Gate source voltage <sup>3)</sup>	$V_{GS}$		±20	V
Power dissipation	P <sub>tot</sub>	T <sub>C</sub> =25 °C	63	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	



#### IPI09N03LA, IPP09N03LA

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	2.4	K/W
SMD version, device on PCB	$R_{\mathrm{thJA}}$	minimal footprint	-	-	62	
		6 cm <sup>2</sup> cooling area <sup>4)</sup>	-	-	40	

### **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### **Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	25	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=20~\mu{\rm A}$	1.2	1.6	2	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS}$ =25 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	-	0.1	1	μΑ
		V <sub>DS</sub> =25 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	10	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5 V, I <sub>D</sub> =30 A	-	12.4	15.5	mΩ
		$V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =30 A, SMD version	-	12.1	15.1	
		V <sub>GS</sub> =10 V, I <sub>D</sub> =30 A	-	7.7	9.2	
		$V_{\rm GS}$ =10 V, $I_{\rm D}$ =30 A, SMD version	-	7.4	8.9	
Gate resistance	R <sub>G</sub>		-	1	-	Ω
Transconductance	g fs	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 30~{\rm A}$	21	42	-	s

 $<sup>^{1)}</sup>$  Current is limited by bondwire; with an  $R_{\rm thJC}$ =2.4 K/W the chip is able to carry 64 A.

<sup>&</sup>lt;sup>2)</sup> See figure 3

 $<sup>^{3)}</sup>$  T  $_{\rm j,max}\!\!=\!\!150$  °C and duty cycle D <0.25 for V  $_{\rm GS}\!\!<\!\!-5$  V

 $<sup>^{4)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm  $^2$  (one layer, 70  $\mu m$  thick) copper area for drain connection. PCB is vertical in still air.



#### IPI09N03LA, IPP09N03LA

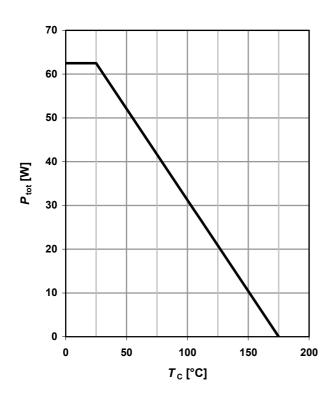
Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	1240	1649	pF
Output capacitance	C oss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =15 V, f=1 MHz	-	530	704	
Reverse transfer capacitance	C <sub>rss</sub>	, , , , , , , , , , , , , , , , , , , ,	-	81	122	
Turn-on delay time	t <sub>d(on)</sub>		-	9	13	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =15 V, V <sub>GS</sub> =10 V,	-	88	132	
Turn-off delay time	$t_{\text{d(off)}}$	$I_D$ =25 A, $R_G$ =2.7 $\Omega$	-	22	33	
Fall time	t <sub>f</sub>		-	4.2	6	
Gate Charge Characteristics <sup>5)</sup>						
Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =15 V, I <sub>D</sub> =25 A, V <sub>GS</sub> =0 to 5 V	-	4.4	5.8	nC
Gate charge at threshold	Q <sub>g(th)</sub>		-	2.0	2.6	
Gate to drain charge	Q <sub>gd</sub>		-	3.1	4.7	
Switching charge	Q sw		-	5.5	7.9	
Gate charge total	Q <sub>g</sub>		-	10	14	
Gate plateau voltage	V <sub>plateau</sub>		-	3.5	-	V
Gate charge total, sync. FET	Q <sub>g(sync)</sub>	V <sub>DS</sub> =0.1 V, V <sub>GS</sub> =0 to 5 V	-	9	12	nC
Output charge	Q oss	V <sub>DD</sub> =15 V, V <sub>GS</sub> =0 V	_	11	15	
Reverse Diode	<b>.</b>			•	<u> </u>	
Diode continous forward current	Is	-T <sub>C</sub> =25 °C	-	-	50	Α
Diode pulse current	I <sub>S,pulse</sub>		-	-	350	1
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =50 A, T <sub>j</sub> =25 °C	-	0.98	1.2	V
Reverse recovery charge	Q <sub>rr</sub>	$V_{R}$ =15 V, $I_{F}$ = $I_{S}$ , $di_{F}/dt$ =400 A/ $\mu$ s	-	-	10	nC

 $<sup>^{5)}</sup>$  See figure 16 for gate charge parameter definition



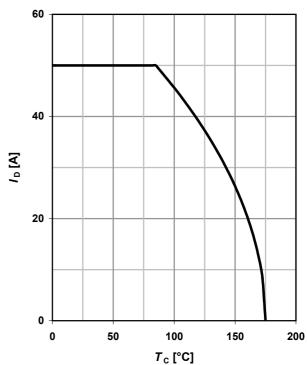
#### 1 Power dissipation

#### $P_{\text{tot}}$ =f( $T_{\text{C}}$ )



#### 2 Drain current

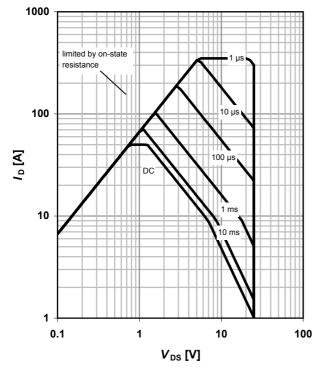
$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



#### 3 Safe operation area

 $I_D = f(V_{DS}); T_C = 25 \,^{\circ}C; D = 0$ 

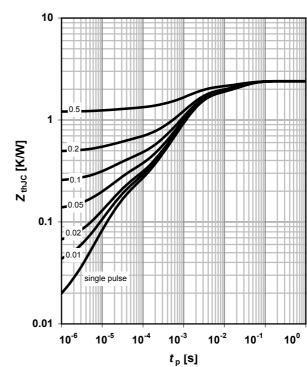
parameter:  $t_p$ 



#### 4 Max. transient thermal impedance

 $Z_{thJC}$ =f( $t_p$ )

parameter:  $D = t_p/T$ 

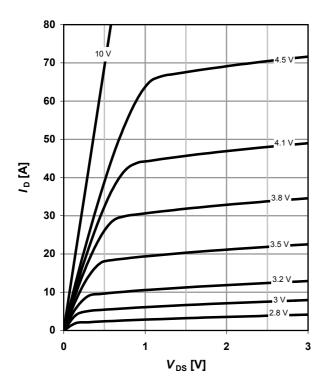




#### 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 \degree C$ 

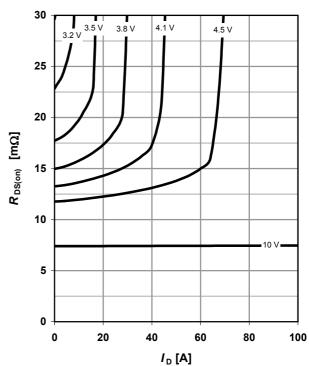
parameter: V<sub>GS</sub>



#### 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

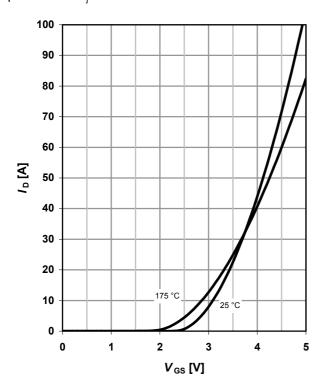
parameter: V<sub>GS</sub>



#### 7 Typ. transfer characteristics

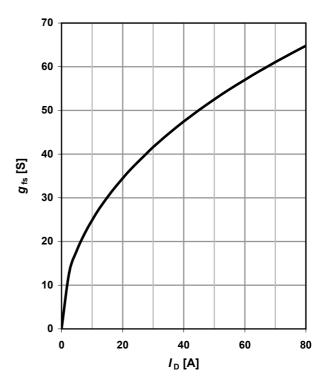
 $I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$ 

parameter: T<sub>j</sub>



#### 8 Typ. forward transconductance

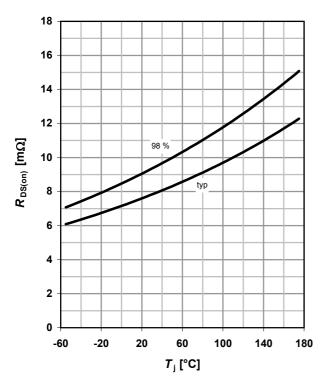
 $g_{fs}$ =f( $I_D$ );  $T_j$ =25 °C





#### 9 Drain-source on-state resistance

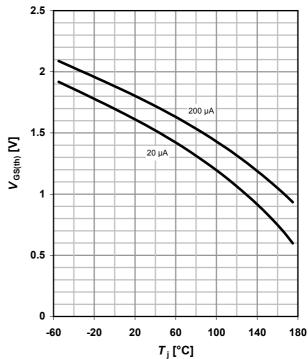
 $R_{DS(on)}$ =f( $T_i$ );  $I_D$ =30 A;  $V_{GS}$ =10 V



#### 10 Typ. gate threshold voltage

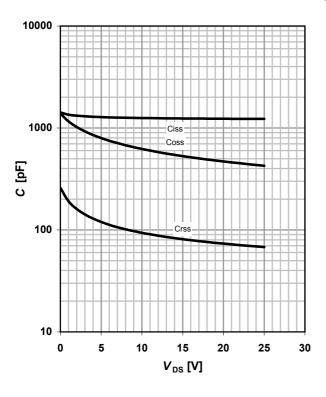
 $V_{GS(th)}=f(T_j); V_{GS}=V_{DS}$ 

parameter: I<sub>D</sub>



#### 11 Typ. Capacitances

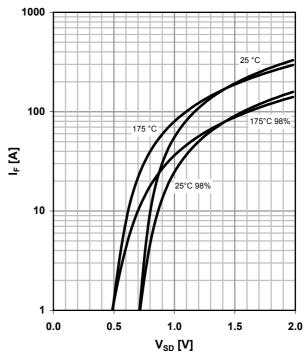
 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 



#### 12 Forward characteristics of reverse diode

 $I_F = f(V_{SD})$ 

parameter: T<sub>j</sub>

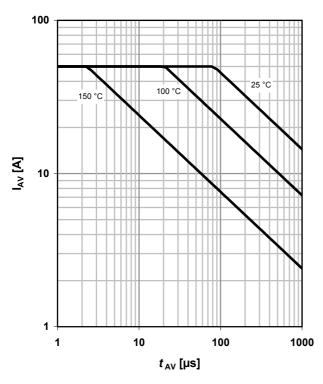




#### 13 Avalanche characteristics

 $I_{AS}$ =f( $t_{AV}$ );  $R_{GS}$ =25  $\Omega$ 

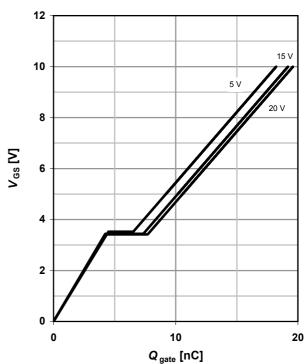
parameter:  $T_{j(start)}$ 



#### 14 Typ. gate charge

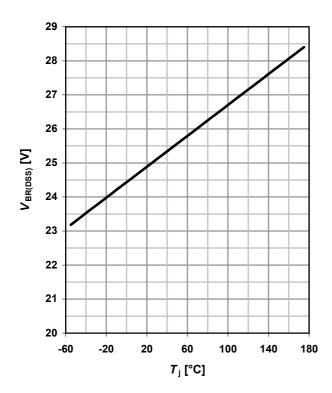
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =25 A pulsed

parameter: V<sub>DD</sub>

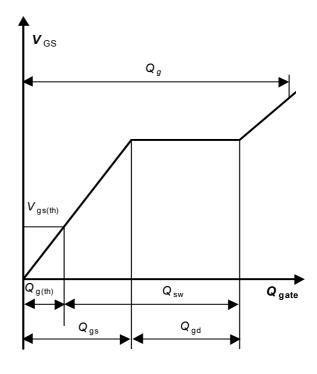


#### 15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =1 mA



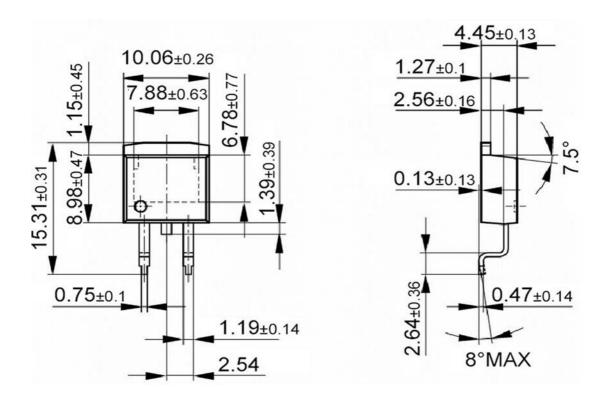
# 16 Gate charge waveforms



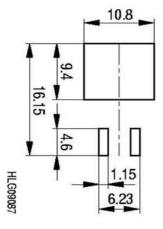


#### **Package Outline**

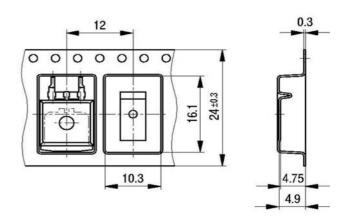
#### P-TO263-3-2: Outline



#### **Footprint**

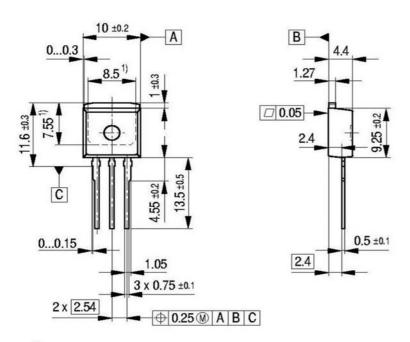


#### **Packaging**



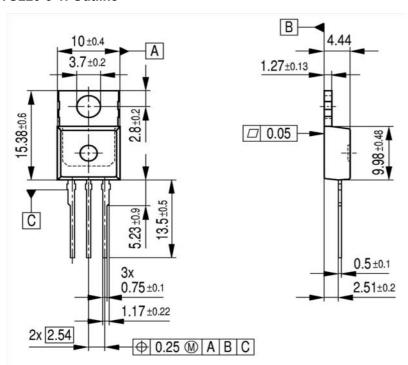


#### P-TO262-3-1: Outline

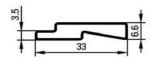


Typical Metal surface min. X = 7.25, Y = 6.9 All metal surfaces tin plated, except area of cut.

#### P-TO220-3-1: Outline



#### **Packaging**



All metal surfaces tin plated, except area of cut. Metal surface min. x=7.25, y=12.3

Dimensions in mm



#### IPI09N03LA, IPP09N03LA

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